

1x1Mx32bit DRAM Card
2x1Mx32bit DRAM Card

MF14M1-J17ATXX
MF18M1-J17ATXX

Connector Type

Two-piece 88-pin

DESCRIPTION

These DRAM CARDS are developed based on JEIDA DRAM CARD GUIDELINE Ver.2.1. These cards are made using industry standard 1M x 4 Dynamic RAM and interface IC's in TSOP.

- 88pin 2 piece connector type.
- RAS only refresh mode, CAS before RAS refresh mode and Page mode functions are available.
- Self refresh mode is available. (128ms/1024cycle)

FEATURES

- Operating Voltage : $V_{cc}=3.3V \pm 5\%$
- All inputs except RAS inputs are buffered.
- Standard card size : 54mm (W) x 85.6mm (L) x 3.3mm (T)

APPLICATIONS

Main/expansion memory unit for Personal Computer, Laser-Printer, FAX etc.

PRODUCT LIST

Product No.	Type name	Item	Memory capacity	Data bus width (bits)	Access time (trAC) (ns)	Connector type	Number of pins	Outline drawing
No. 1	MF14M1-J17ATXX		4 MB	32	70	Two-piece	88	88P-002
No. 2	MF18M1-J17ATXX		8 MB					

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PIN ASSIGNMENT (No.1)

Pin No.	Symbol	Function	Pin No.	Symbol	Function	
1	GND	Ground	45	GND	Ground	
2	DQ 0	Data I/O	46	DQ18	Data I/O	
3	DQ 1		47	DQ19		
4	DQ 2		48	DQ20		
5	DQ 3		49	DQ21		
6	DQ 4		50	DQ22		
7	DQ 5		51	DQ23		
8	DQ 6		52	DQ24		
9	N.C.		No connection	53		DQ25
10	DQ 7	Data I/O	54	N.C.		
11	Vcc	Power supply voltage	55	N.C.	Ground	
12	N.C.	No connection	56	GND		
13	A 0	Address input	57	A 1	Address input	
14	A 2		58	A 3		
15	N.C.		No connection	59		A 5
16	A 4		Address input	60		A 7
17	Vcc	Power supply voltage	61	A 9	No connection	
18	A 6	Address input	62	N.C.		
19	A 8		Address input	63	GND	Ground
20	N.C.	No connection	64	N.C.	No connection	
21	N.C.		No connection	65		N.C.
22	RAS 0	Row address strobe 0	66	CAS 2	Column address strobe 2	
23	CAS 0	Column address strobe 0	67	GND	Ground	
24	CAS 1	Column address strobe 1	68	CAS 3	Column address strobe 3	
25	Vcc	Power supply voltage	69	N.C.	No connection	
26	RAS 2	Row address strobe 2	70	WE	Write enable	
27	N.C.	No connection	71	PD 1 (GND)	Presence detect 1	
28	PD 2 (N.C.)	Presence detect 2	72	PD 3 (GND)	Presence detect 3	
29	PD 4 (GND)	Presence detect 4	73	GND	Ground	
30	PD 6 (GND)	Presence detect 6	74	PD 5 (N.C.)	Presence detect 5	
31	N.C.	No connection	75	PD 7 (N.C.)	Presence detect 7	
32	N.C.		No connection	76	PD 8 (GND)	Presence detect 8
33	N.C.		No connection	77	N.C.	No connection
34	DQ 9	Data I/O	78	PD 9 (N.C.)	Presence detect 9	
35	Vcc	Power supply voltage	79	N.C.	Data I/O	
36	DQ10	Data I/O	80	DQ27		
37	N.C.	No connection	81	DQ28		
38	DQ11	Data I/O	82	DQ29		
39	DQ12		83	DQ30		
40	DQ13		84	DQ31		
41	DQ14		85	DQ32		
42	DQ15		86	DQ33		
43	DQ16		87	DQ34		
44	GND	Ground	88	GND	Ground	

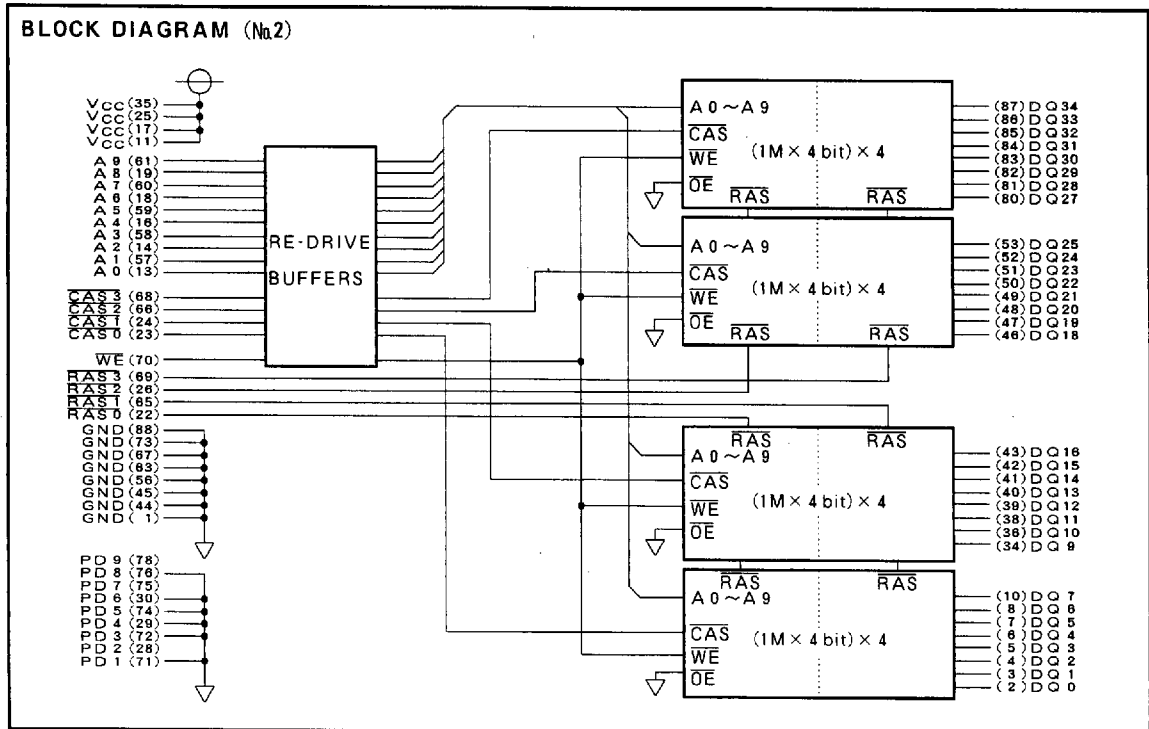
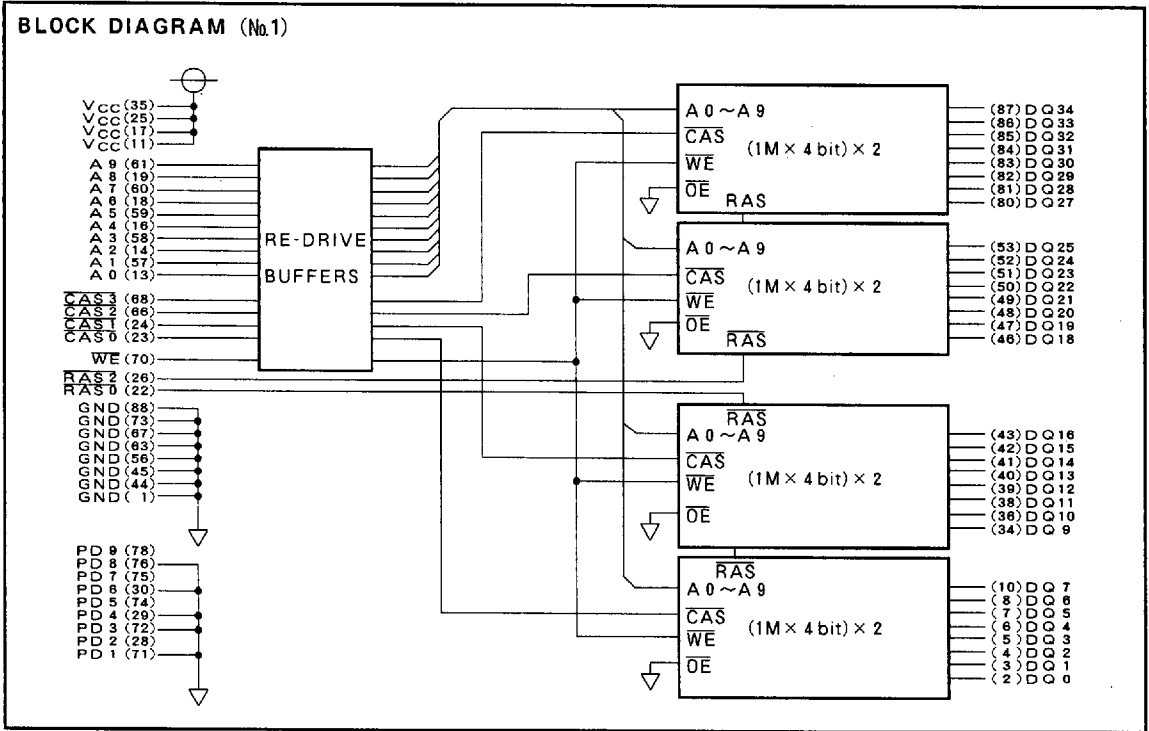
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PIN ASSIGNMENT (No.2)

Pin No.	Symbol	Function	Pin No.	Symbol	Function	
1	GND	Ground	45	GND	Ground	
2	DQ 0	Data I/O	46	DQ18	Data I/O	
3	DQ 1					
4	DQ 2					
5	DQ 3					
6	DQ 4					
7	DQ 5					
8	DQ 6					
9	N.C.		No connection	52		DQ24
10	DQ 7	Data I/O	53	DQ25		
11	V _{CC}	Power supply voltage	54	N.C.		
12	N.C.	No connection	55	N.C.		
13	A 0	Address input	56	GND	Ground	
14	A 2					
15	N.C.		No connection	57	A 1	Address input
16	A 4	Address input	58	A 3		
17	V _{CC}	Power supply voltage	59	A 5		
18	A 6	Address input	60	A 7		
19	A 8					
20	N.C.		No connection	61	A 9	
21	N.C.	No connection	62	N.C.	No connection	
22	<u>RAS 0</u>	Row address strobe 0	63	GND	Ground	
23	<u>CAS 0</u>	Column address strobe 0	64	N.C.	No connection	
24	<u>CAS 1</u>	Column address strobe 1	65	<u>RAS 1</u>	Row address strobe 1	
25	V _{CC}	Power supply voltage	66	<u>CAS 2</u>	Column address strobe 2	
26	<u>RAS 2</u>	Row address strobe 2	67	<u>GND</u>	Ground	
27	N.C.	No connection	68	<u>CAS 3</u>	Column address strobe 3	
28	PD 2 (N.C.)	Presence detect 2	69	<u>RAS 3</u>	Row address strobe 3	
29	PD 4 (GND)	Presence detect 4	70	WE	Write enable	
30	PD 6 (GND)	Presence detect 6	71	PD 1 (GND)	Presence detect 1	
31	N.C.	No connection	72	PD 3 (GND)	Presence detect 3	
32	N.C.					
33	N.C.					
34	DQ 9	Data I/O	73	GND	Ground	
35	V _{CC}	Power supply voltage	74	PD 5 (GND)	Presence detect 5	
36	DQ 10	Data I/O	75	PD 7 (N.C.)	Presence detect 7	
37	N.C.	No connection	76	PD 8 (GND)	Presence detect 8	
38	DQ 11	Data I/O	77	N.C.	No connection	
39	DQ 12					
40	DQ 13					
41	DQ 14					
42	DQ 15					
43	DQ 16					
44	GND		Ground	78	PD 9 (N.C.)	Presence detect 9
				79	N.C.	No connection
			80	DQ 27	Data I/O	
			81	DQ 28		
			82	DQ 29		
			83	DQ 30		
			84	DQ 31		
			85	DQ 32		
			86	DQ 33		
			87	DQ 34		
			88	GND	Ground	

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FUNCTION TABLE

Operation	Input					input/output		Refresh	Note
	$\overline{\text{RAS}}$	$\overline{\text{CAS}}$	$\overline{\text{WE}}$	Row Address	Column Address	input	output		
Read	ACT	ACT	NAC	APD	APD	OPD	VLD	YES	Page mode identical
Early write	ACT	ACT	ACT	APD	APD	VLD	OPN	YES	
RAS-only refresh	ACT	NAC	DNC	APD	DNC	DNC	OPN	YES	
CAS before RAS refresh	ACT	ACT	NAC	DNC	DNC	DNC	OPN	YES	
Self refresh	ACT	ACT	NAC	DNC	DNC	DNC	OPN	YES	
Standby	NAC	DNC	DNC	DNC	DNC	DNC	OPN	NO	

Note 1 : ACT : active, NAC : nonactive, DNC : don't care, VLD : valid, APD : applied, OPN : open
 Odd numbered RAS signals (RAS1, RAS3) and even numbered RAS signals (RAS0, RAS2)
 should not be active at the same time during Read and Early Write cycles.
 This comment does not apply to MF14M1-J17ATXXseries cards.

ABSOLUTE MAXIMUM RATINGS

Symbol	Parameter	Conditions	Ratings		Unit
V _{CC}	Supply voltage	With respect to GND	-0.5~4.6		V
V _I	Input voltage		-0.5~4.6		V
V _O	Output voltage		-0.5~4.6		V
I _O	Output current		50		mA
P _d	Power dissipation	T _a = 25°C	No.1 8	No.2 16	W
T _{opr}	Operating temperature		0~55		°C
T _{stg}	Storage temperature		-40~80		°C

RECOMMENDED OPERATING CONDITIONS (T_a = 0 ~ 55°C, unless otherwise noted) : (Note 2)

Symbol	Parameter	Limits			Unit
		Min.	Typ.	Max.	
V _{CC}	Supply voltage	3.315	3.3	3.465	V
GND	Supply voltage	0	0	0	V
V _{IH}	High input voltage	2.0		V _{CC}	V
V _{IL}	Low input voltage	0.		0.8	V

Note 2 : With respect to GND

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ELECTRICAL CHARACTERISTICS ($T_a = 0 \sim 55^\circ\text{C}$, $V_{CC} = 3.3\text{V} \pm 5\%$, $\text{GND} = 0\text{V}$) : (Note 3)

Symbol	Parameter	Test condition	Limits				Unit
			Min.		Max.		
V_{OH}	High-level output voltage	$I_{OH} = -2\text{mA}$	2.4		V_{CC}		V
V_{OL}	Low-level output voltage	$I_{OL} = 2\text{mA}$	0		0.4		V
I_{OZ}	Off-state output current	$0\text{V} \leq V_{out} \leq V_{CC}$	No.1 -10	No.2 -20	No.1 10	No.2 20	μA
I_I	Input current	$0\text{V} \leq V_{in} \leq V_{CC}$ other input pins = 0V	-40		40		μA
$I_{CC1(AV)}$	Average supply current from V_{CC} , operating (Note 4, 5, 6)	$\overline{\text{RAS}}, \overline{\text{CAS}}$ cycling $t_{RC} = t_{WC} = \text{min}$, output open			No.1 600	No.2 610	mA
$I_{CC2(AV)}$	Supply current from V_{CC} , Standby (Note 7)	$\overline{\text{RAS}} = \overline{\text{CAS}} \geq V_{CC} - 0.2\text{V}$ other input pins $\geq V_{CC} - 0.2\text{V}$ or $\leq 0.2\text{V}$, output open			No.1 0.5	No.2 0.9	mA
$I_{CC3(AV)}$	Average supply current from V_{CC} , refreshing (Note 4, 6)	$\overline{\text{RAS}}$ cycling, $\overline{\text{CAS}} = V_{IH}$ $t_{RC} = \text{min}$, output open			No.1 590	No.2 1160	mA
$I_{CC4(AV)}$	Average supply current from V_{CC} , Page-mode (Note 4, 5, 6)	$\overline{\text{RAS}} = V_{IL}$, $\overline{\text{CAS}}$ cycling $t_{RC} = \text{min}$, output open			No.1 560	No.2 580	mA
$I_{CC6(AV)}$	Average supply current from V_{CC} , $\overline{\text{CAS}}$ before $\overline{\text{RAS}}$ refresh mode (Note 4, 6)	$\overline{\text{CAS}}$ before $\overline{\text{RAS}}$ refresh cycling $t_{RC} = \text{min}$, output open			No.1 490	No.2 970	mA
$I_{CC8(AV)}$	Average supply current from V_{CC} , Extended refresh mode (Note 7)	$\overline{\text{CAS}}$ before $\overline{\text{RAS}}$ refresh cycling $\overline{\text{WE}} \geq V_{CC} - 0.2\text{V}$ other input pins $\geq V_{CC} - 0.2\text{V}$ or $\leq 0.2\text{V}$, output open $t_{RC} = 125\mu\text{s}$, $t_{RAS} = t_{RAS}(\text{min})$ $\sim 1\mu\text{s}$			No.1 1	No.2 2	mA
$I_{CC9(AV)}$	Average supply current from V_{CC} , Self refresh mode (Note 7)	$\overline{\text{RAS}} = \overline{\text{CAS}} \leq 0.2\text{V}$, $\overline{\text{WE}} \geq V_{CC} - 0.2\text{V}$ output open			No.1 1	No.2 2	mA

- Note 3 : Current flowing into a CARD is positive, out is negative.
 4 : $I_{CC1(AV)}$, $I_{CC3(AV)}$, $I_{CC4(AV)}$ and $I_{CC6(AV)}$ are dependent on cycle rate.
 Specified values are obtained at the fastest cycle rate.
 5 : $I_{CC1(AV)}$ and $I_{CC4(AV)}$ are dependent on output loading.
 Specified values are obtained with the outputs open.
 6 : Column Address can be changed once or less while $\overline{\text{RAS}} = V_{IL}$ and $\overline{\text{CAS}} = V_{IH}$.

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SWITCHING CHARACTERISTICS (T_a = 0 ~ 55°C, V_{CC} = 3.3V ± 5%, GND = 0V) : (Note 7)

Symbol	Parameter	Limits		Unit
		Min.	Max.	
t _{CAC}	Access time from $\overline{\text{CAS}}$ (Note 8, 9)		27	ns
t _{RAC}	Access time from $\overline{\text{RAS}}$ (Note 8, 10)		70	ns
t _{CAA}	Column Address access time (Note 8, 11)		42	ns
t _{OFF}	Output disable time after $\overline{\text{CAS}}$ high (Note 12)	0	27	ns

Note 7 : An initial pause of 500 μs is required after power-up followed by any 8 $\overline{\text{RAS}}$ or $\overline{\text{RAS}}/\overline{\text{CAS}}$ cycles before proper device operation is achieved.

Note that $\overline{\text{RAS}}$ may be cycled during the initial pause. And any 8 $\overline{\text{RAS}}$ or $\overline{\text{RAS}}/\overline{\text{CAS}}$ cycles are required after prolonged periods of $\overline{\text{RAS}}$ inactivity before proper device operation is achieved.

8 : Measured with a load circuit equivalent to 100pF and V_{OH} = 2.4V (I_{OH} = -2 mA), V_{OL} = 0.4V (I_{OL} = 2 mA). The reference levels for measuring of output signals are 2.0V (V_{OH}) and 0.8V (V_{OL}).

9 : Assumes that t_{RCD} ≥ t_{RCD}(max) and t_{ASC} ≥ t_{ASC}(max).

10 : Assumes that t_{RCD} ≤ t_{RCD}(max) and t_{RAD} ≤ t_{RAD}(max).

11 : Assumes that t_{RAD} ≥ t_{RAD}(max) and t_{ASC} ≤ t_{ASC}(max).

12 : t_{OFF} (max) defines the time at which the output achieves the high impedance state (MF14M1-J17ATXX : I_{outI} ≤ 10 μA, MF18M1-J17ATXX : I_{outI} ≤ 20 μA) and are not reference to V_{OH}(min) or V_{OL}(max).

TIMING REQUIREMENTS (T_a = 0 ~ 55°C, V_{CC} = 3.3V ± 5%, GND = 0V) : (Note 13, 14)

Symbol	Parameter	Limits		Unit
		Min.	Max.	
t _{REF}	Refresh cycle time		128	ms
t _{RP}	$\overline{\text{RAS}}$ high pulse width	50		ns
t _{RCD}	Delay time, $\overline{\text{RAS}}$ low to $\overline{\text{CAS}}$ low (Note15)	20	43	ns
t _{CRP}	Delay time, $\overline{\text{CAS}}$ high to $\overline{\text{RAS}}$ low (Note16)	17		ns
t _{RPC}	Precharge to $\overline{\text{CAS}}$ active time.	0		ns
t _{CPN}	$\overline{\text{CAS}}$ high pulse width	10		ns
t _{RAD}	Column address delay time from $\overline{\text{RAS}}$ low (Note 17)	17	28	ns
t _{ASR}	Row address setup time before $\overline{\text{RAS}}$ low	10		ns
t _{ASC}	Column address setup time before $\overline{\text{CAS}}$ low (Note18)	5	10	ns
t _{RAH}	Row address hold time after $\overline{\text{RAS}}$ low	10		ns
t _{CAH}	Column address hold time after $\overline{\text{CAS}}$ low	15		ns
t _T	Transition time (Note19)	3	50	ns

Note 13 : The timing requirements are assumed t_T = 5 ns.

14 : V_{IH}(min) and V_{IL}(max) are reference levels for measuring timing of input signals.

15 : t_{RCD}(max) is specified as a reference point only.

If t_{RCD} ≥ t_{RCD}(max), access time is defined as t_{CAC} and t_{CAA}.

16 : t_{CRP} requirement is applicable for all $\overline{\text{RAS}}/\overline{\text{CAS}}$ cycles.

17 : t_{RAD}(max) is specified as a reference point only.

If t_{RAD} ≥ t_{RAD}(max) and t_{ASC} ≤ t_{ASC}(max), access time is assumed by t_{CAA} for read cycle.

18 : t_{ASC}(max) is specified as a reference point only of address access time.

19 : t_T is measured between V_{IH}(min) and V_{IL}(max).

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Read and Refresh Cycles

Symbol	Parameter	Limits		Unit
		Min.	Max.	
tRC	Read cycle time	130		ns
tRAS	RAS low pulse width	70	10000	ns
tCAS	CAS low pulse width	20	10000	ns
tCSH	CAS hold time after RAS low	70		ns
tRSH	RAS hold time after CAS low	27		ns
tRSC	Read setup time before CAS low	5		ns
tRCH	Read hold time after CAS high	0		ns
tRRH	Read hold time after RAS high	10		ns

Write Cycle (Early Write)

Symbol	Parameter	Limits		Unit
		Min.	Max.	
tWC	Write cycle time	130		ns
tRAS	RAS low pulse width	70	10000	ns
tCAS	CAS low pulse width	20	10000	ns
tCSH	CAS hold time after RAS low	70		ns
tRSH	RAS hold time after CAS low	27		ns
twCS	Write setup time before CAS low	5		ns
twCH	Write hold time after CAS low	15		ns
tDS	Data setup time	10		ns
tDH	Data hold time after CAS low	22		ns

Page Mode Cycle (Read, Early Write)

Symbol	Parameter	Limits		Unit
		Min.	Max.	
tpC	Read, Write cycle time	55		ns
tcp	CAS high pulse width	10		ns
tRAS	RAS low pulse width (Note 20)	125	100000	ns

Note 20 : tRAS(min) is specified by the following formula as two cycles of CAS input are executed.
 $tRAS(min) = tCSH(min) + tpC(min)$.

CAS before RAS Refresh Cycle (Note 21)

Symbol	Parameter	Limits		Unit
		Min.	Max.	
tCSR	CAS setup time for CAS before RAS refresh	20		ns
tCHR	CAS hold time for CAS before RAS refresh	15		ns

Note 21 : Eight or more CAS before RAS cycles are necessary for proper operation of CAS before RAS refresh mode.

Self Refresh Cycle

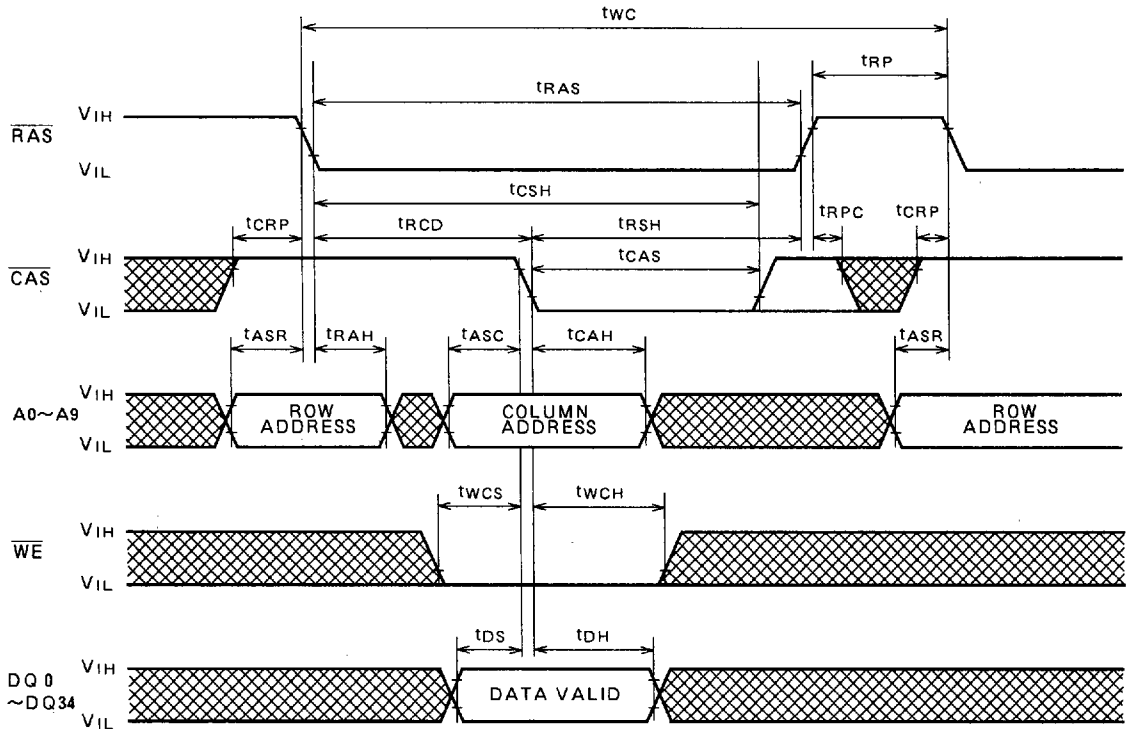
Symbol	Parameter	Limits		Unit
		Min.	Max.	
tRASS	RAS low pulse width	100		μs
tRPS	CAS high pulse width	130		ns
tCHS	RAS hold time after RAS high	-50		ns

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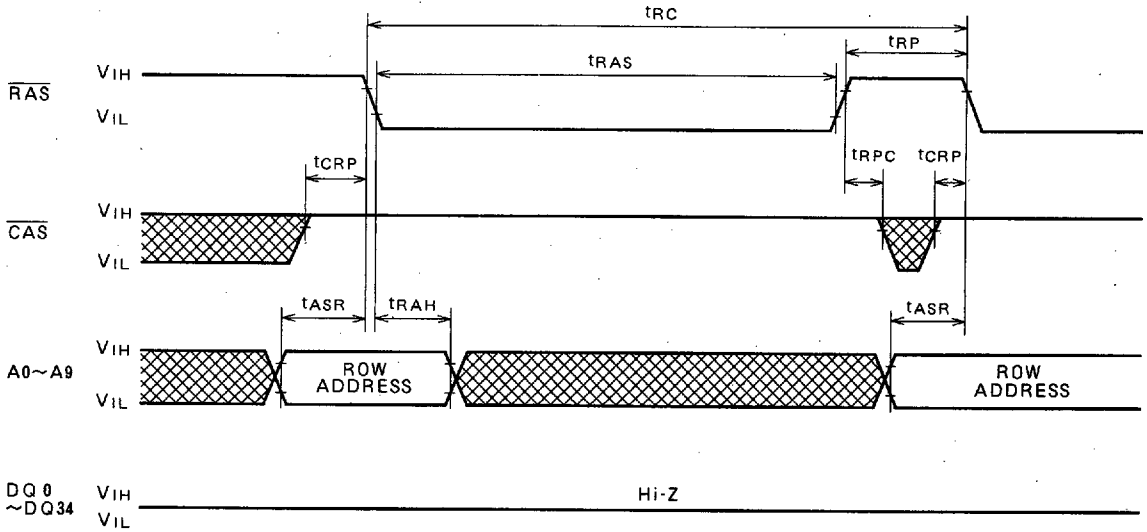
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Early Write Cycle



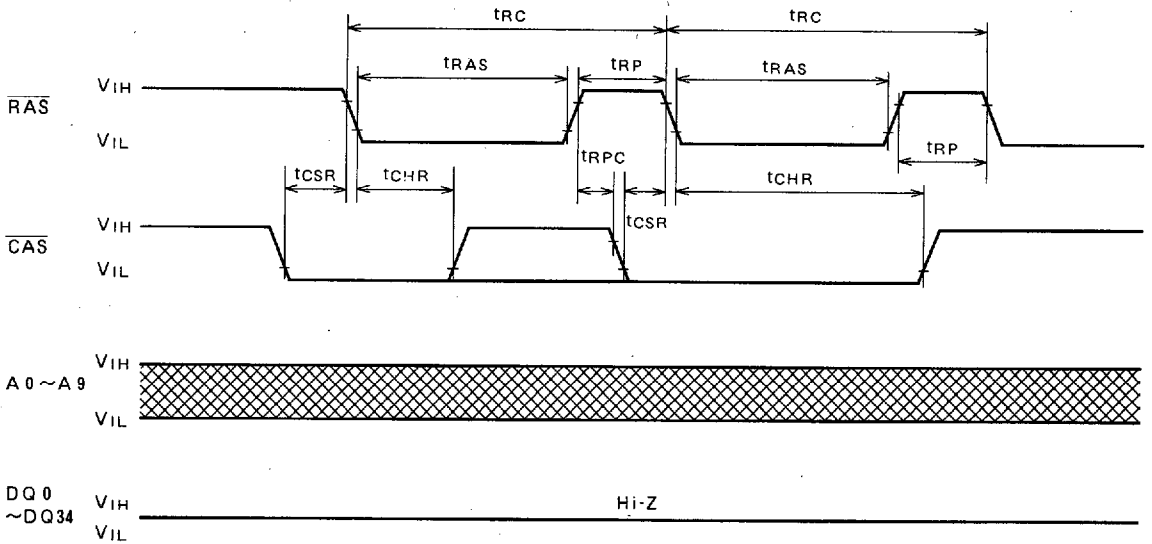
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RAS only Refresh Cycle (Note 23)



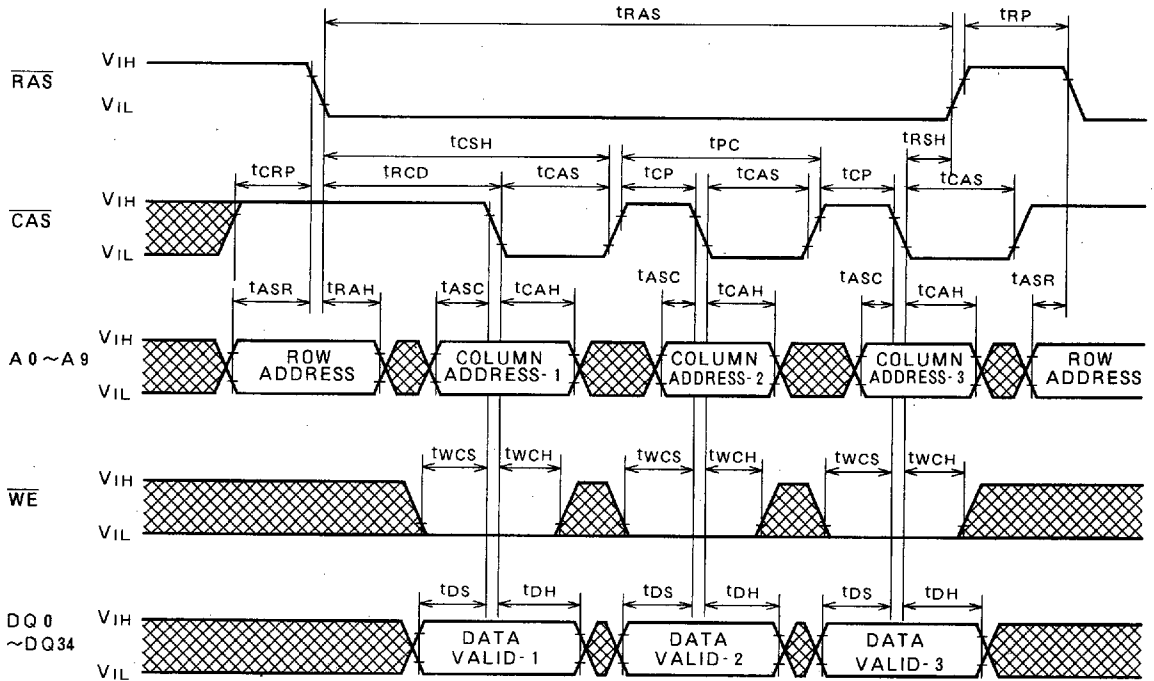
Note 23 : $\overline{WE} = \text{don't care}$

CAS before RAS Refresh Cycle (Note 24)



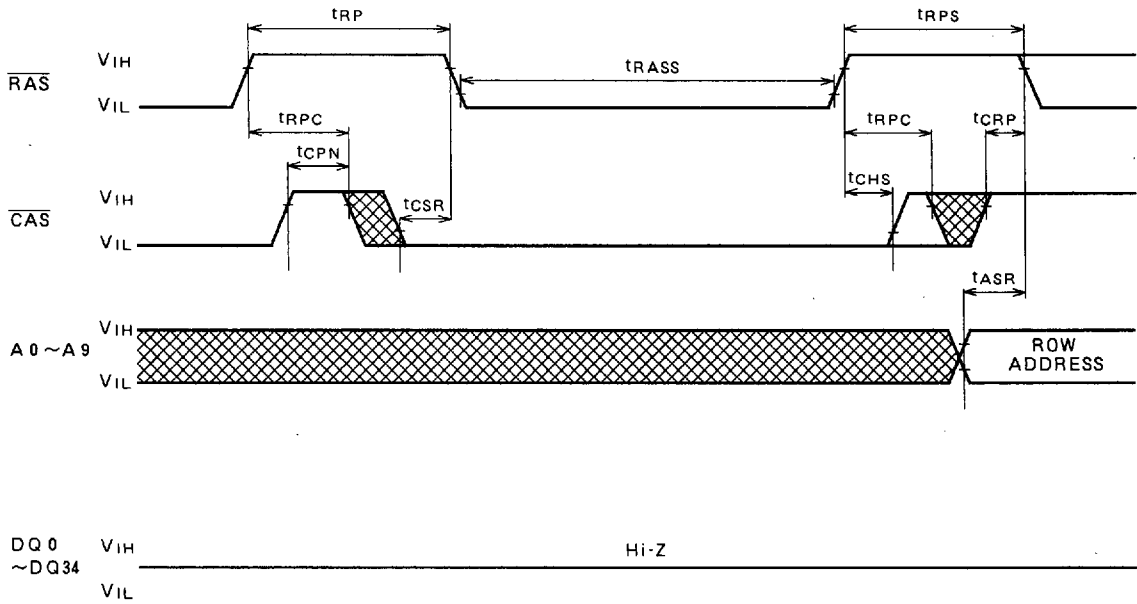
Note 24 : $\overline{WE} = V_{IH}$

Page-Mode Early Write Cycle



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Self Refresh Cycle (Note 25, 26)



Note 25 : $\overline{WE} = V_{IH}$

Note 26 : Self refresh sequence

Two refresh methods can be selected depending on the low pulse width (t_{RASS}) of \overline{RAS} signal during the self refresh period.

1. In case of $t_{RASS} < 300ms$

1.1 Distributed refresh during Read/Write operation

(A) Timing diagram

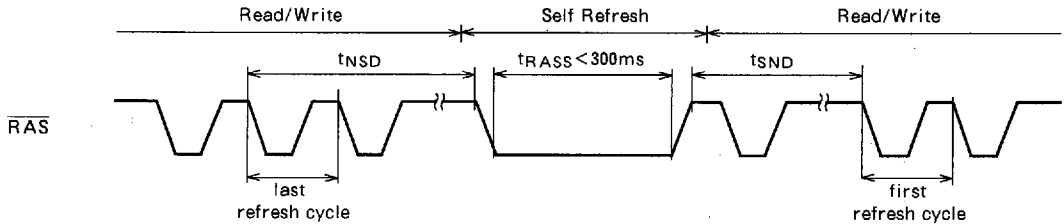
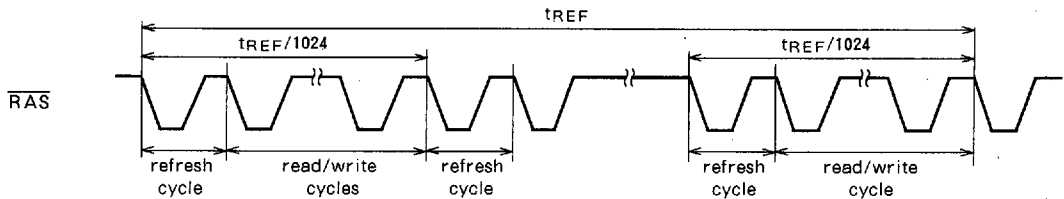


Table 1

Read/Write	Read/Write → Self refresh	Self refresh → Read/Write
CBR distributed refresh	$t_{NSD} + t_{SND} \leq 16.4ms$	
\overline{RAS} only distributed refresh	$t_{NSD} \leq 16\mu s$	$t_{SND} \leq 16\mu s$

(B) Definition of distributed refresh



Definition of CBR distributed refresh

The CBR distributed refresh performs more than 1024 constant period ($125\mu s$ max) CBR cycles within 128 ms.

Definition of \overline{RAS} only distributed refresh

All combinations of ten row address signals ($A_0 \sim A_9$) are selected during 1024 constant period ($16\mu s$ max) \overline{RAS} only refresh cycles within 16.4ms.

Note :

$\overline{RAS}/\overline{CAS}$ refresh may be used instead of \overline{RAS} only refresh.

1.1.1 CBR distributed refresh

- Switching from read/write operation to self refresh operation.

The time interval from the falling edge of \overline{RAS} signal in the last CBR refresh cycle during read/write operation period to the falling edge of \overline{RAS} signal at the start of self refresh operation should be set within t_{NSD} (shown in table).

- Switching from self refresh operation to read/write operation.

The time interval from the rising edge of \overline{RAS} signal at the end of self refresh operation to the falling edge of \overline{RAS} signal in the first CBR refresh cycle during read/write operation period should be set within t_{SND} (shown in table).

1.1.2 \overline{RAS} only distributed refresh

- Switching from read/write operation to self refresh operation.

The time interval t_{NSD} from the falling edge of \overline{RAS} signal in the last \overline{RAS} only refresh cycle during read/write operation period to the falling edge of \overline{RAS} signal at the start of self refresh operation should be set within $16\mu s$.

- Switching from self refresh operation to read/write operation.

The time interval t_{SND} from the rising edge of \overline{RAS} signal at the end of self refresh operation to the falling edge of \overline{RAS} signal in the first CBR refresh cycle during read/write operation period should be set within $16\mu s$.

1. 2 Burst refresh during Read/Write operation

(A) Timing diagram

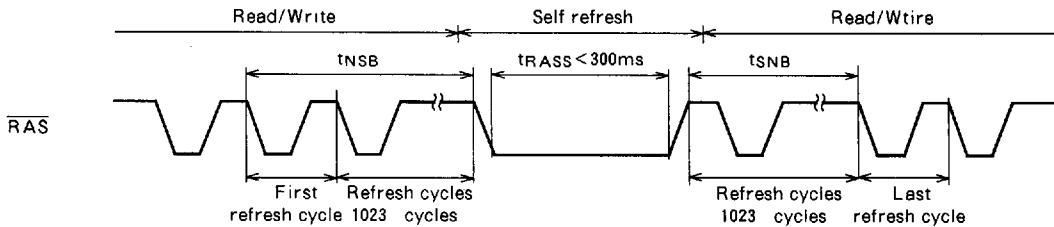
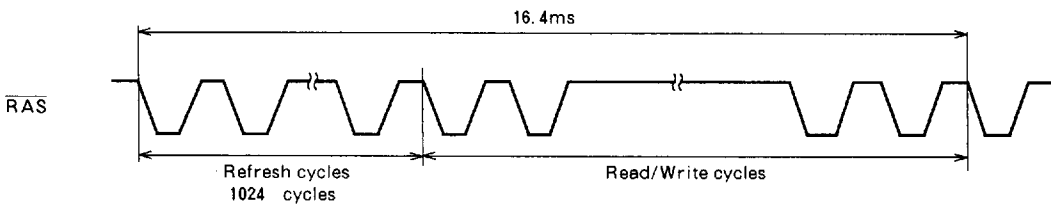


Table 2

Read/Write	Read/Write → Self refresh	Self refresh → Read/Write
CBR burst refresh	$t_{NSB} \leq 16.4\text{ms}$	$t_{NSB} \leq 16.4\text{ms}$
RAS only burst refresh	$t_{NSB} + t_{NSB} \leq 16.4\text{ms}$	

(B) Definition of burst refresh



Definition of CBR burst refresh

The CBR burst refresh performs more than 1024 continuous CBR cycles within 16.4ms.

Definition of RAS only burst refresh

All combinations of ten row address signals ($A_0 \sim A_9$) are selected during 1024 continuous RAS only refresh cycles within 16.4ms.

1. 2. 1 CBR burst refresh

- Switching from read/write operation to self refresh operation.

The time interval t_{NSB} from the falling edge of $\overline{\text{RAS}}$ signal in the first CBR refresh cycle during read/write operation period to the falling edge of $\overline{\text{RAS}}$ signal at the start of self refresh operation should be set within 16.4ms.

- Switching from self refresh operation to read/write operation.

The time interval t_{NSB} from the rising edge of $\overline{\text{RAS}}$ signal at the end of self refresh operation to the falling edge of $\overline{\text{RAS}}$ signal in the last CBR refresh cycle during read/write operation period should be set within 16.4ms.

1. 2. 2 $\overline{\text{RAS}}$ only burst refresh

- Switching from read/write operation to self refresh operation.

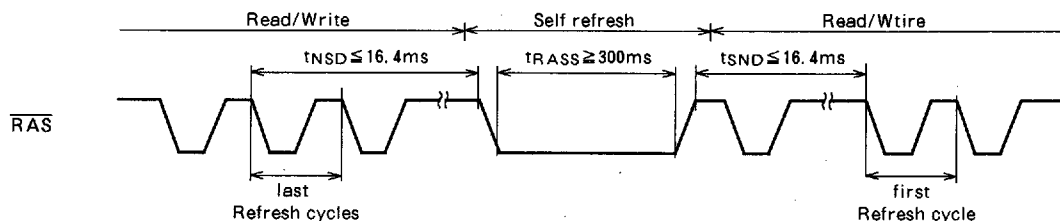
The time interval from the falling edge of $\overline{\text{RAS}}$ signal in the first RAS only refresh cycle during read/write operation period to the falling edge of $\overline{\text{RAS}}$ signal at the start of self refresh operation should be set within t_{NSB} (shown in table 2).

- Switching from self refresh operation to read/write operation.

The time interval from the rising edge of $\overline{\text{RAS}}$ signal at the end of self refresh operation to the falling edge of $\overline{\text{RAS}}$ signal in the last RAS only refresh cycle during read/write operation period should be set within t_{NSB} (shown in table 2).

2. In case of $t_{RAS} \geq 300ms$

(A) Timing diagram-A



Timing diagram-B

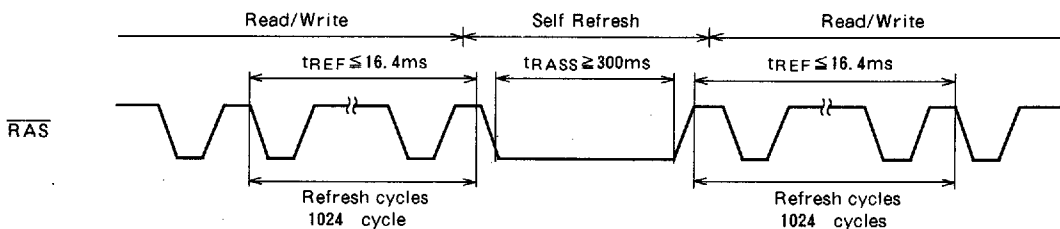


Table 3

Read/Write	Read/Write→Self refresh	Self refresh→Read/Write
CBR distributed refresh	Timing diagram-A	Timing diagram-A
RAS only distributed refresh CBR burst refresh RAS only burst refresh	Timing diagram-B	Timing diagram-B

(B) Definition of refresh

The same as 1. 1 -(B) and 1. 2 -(B)

2. 1. 1 CBR distributed refresh

- Switching from read/write operation to self refresh operation.

The time interval t_{NSD} from the falling edge of \overline{RAS} signal in the last CBR refresh cycle during read/write operation period to the falling edge of \overline{RAS} signal at the start of self refresh operation should be set within 16.4ms.

- Switching from self refresh operation to read/write operation.

The time interval t_{NSD} from the rising edge of \overline{RAS} signal at the end of self refresh operation to the falling edge of \overline{RAS} signal in the first CBR refresh cycle during read/write operation period should be set within 16.4ms.

2. 1. 2 \overline{RAS} only distributed, CBR burst, \overline{RAS} only burst refresh

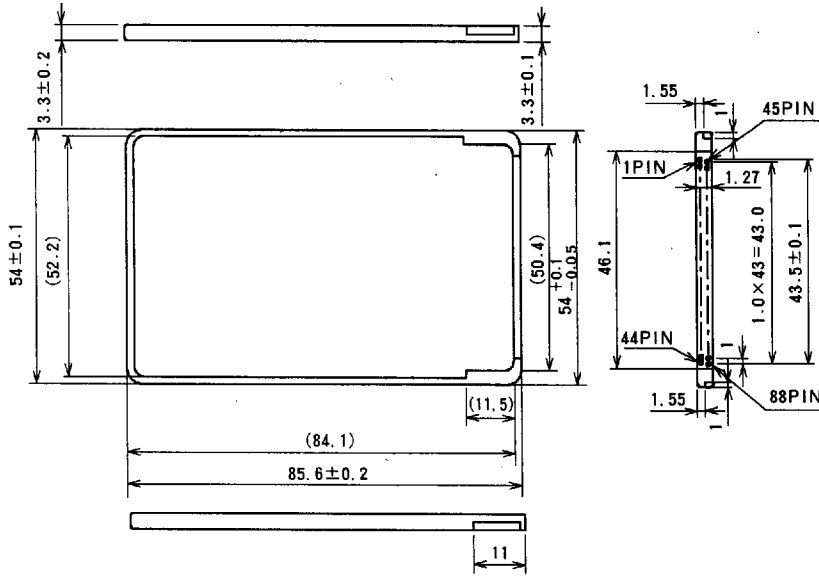
- Before and after the self refresh, 1024 refresh cycles should be executed within 16.4ms for each refresh operation.

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88P-001

TWO - PIECE 88 pin (5V connector keying)

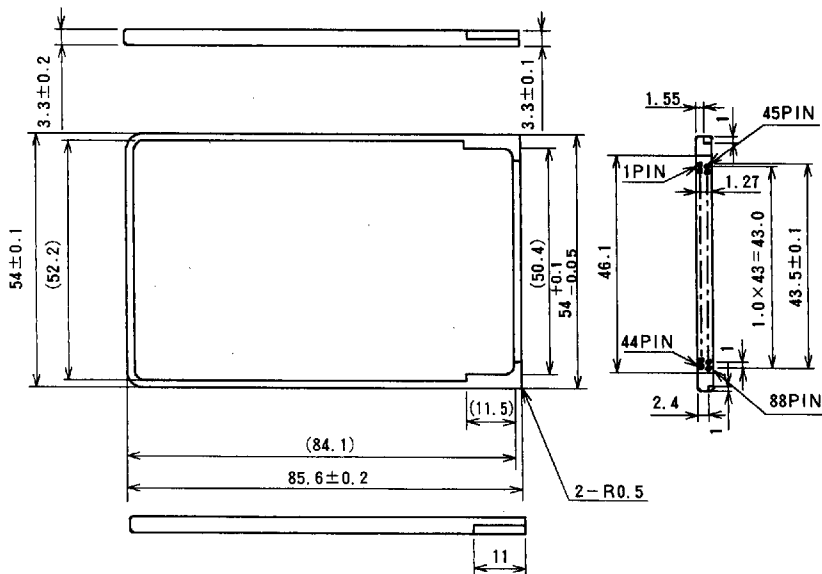
Dimensions in mm



88P-002

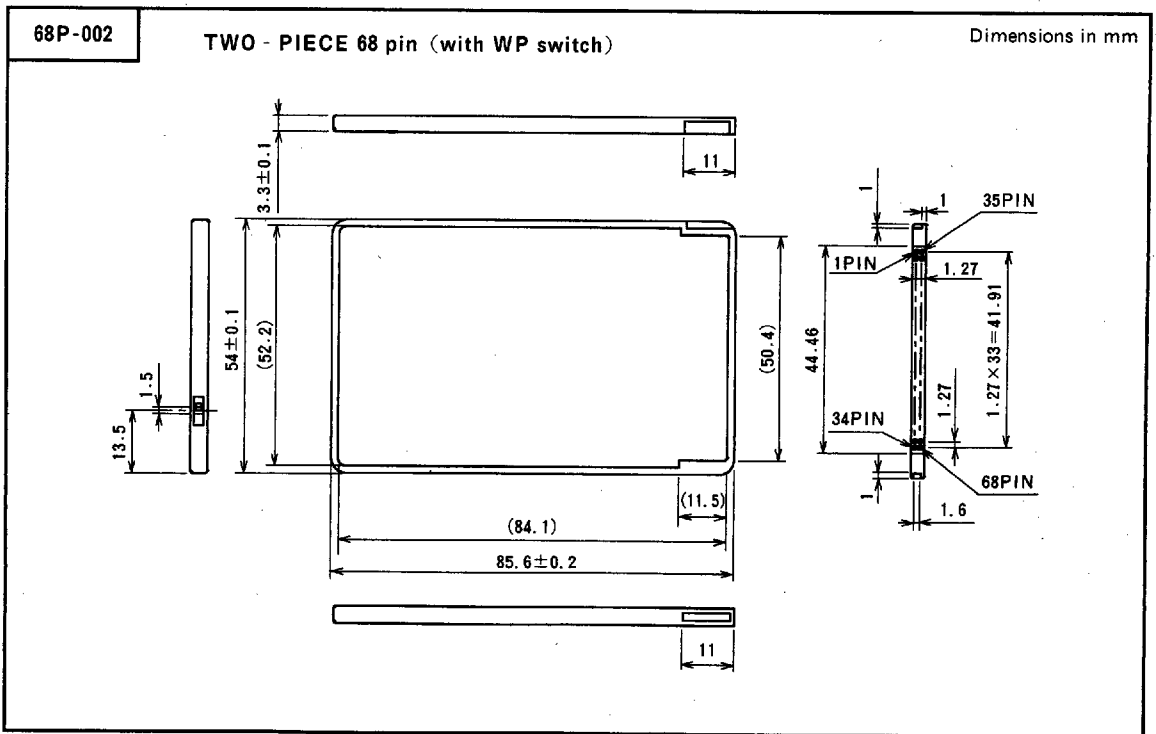
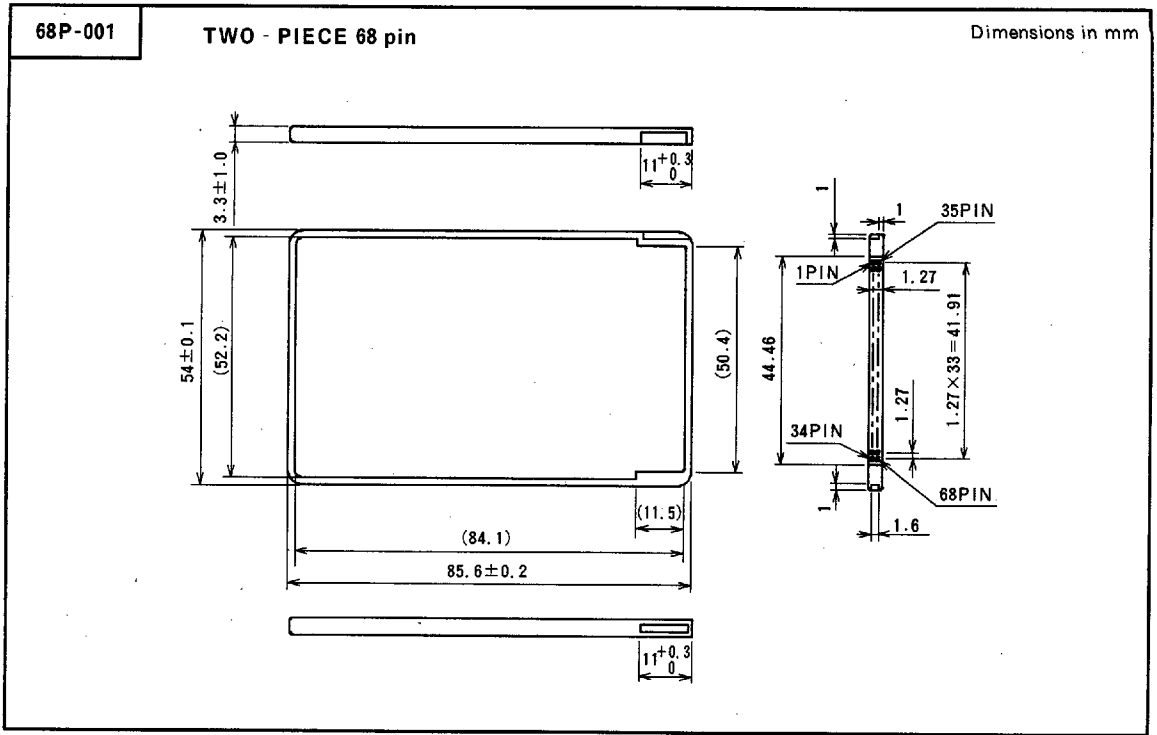
TWO - PIECE 88 pin (3.3V connector keying)

Dimensions in mm



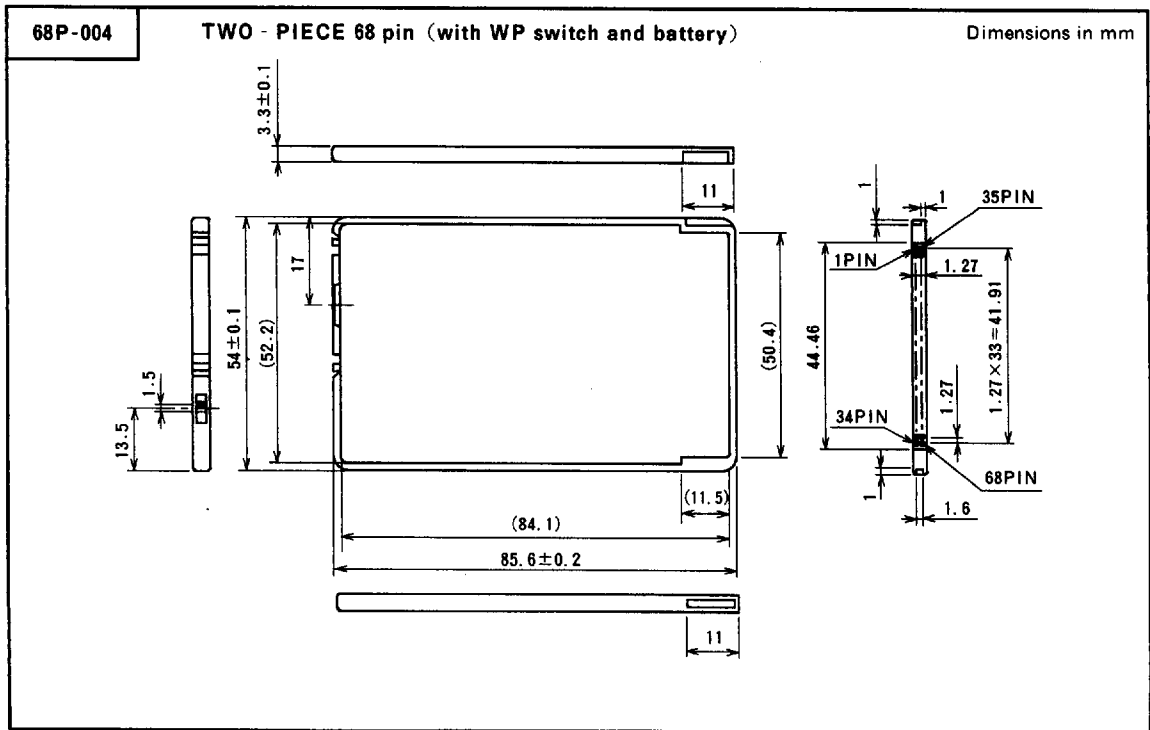
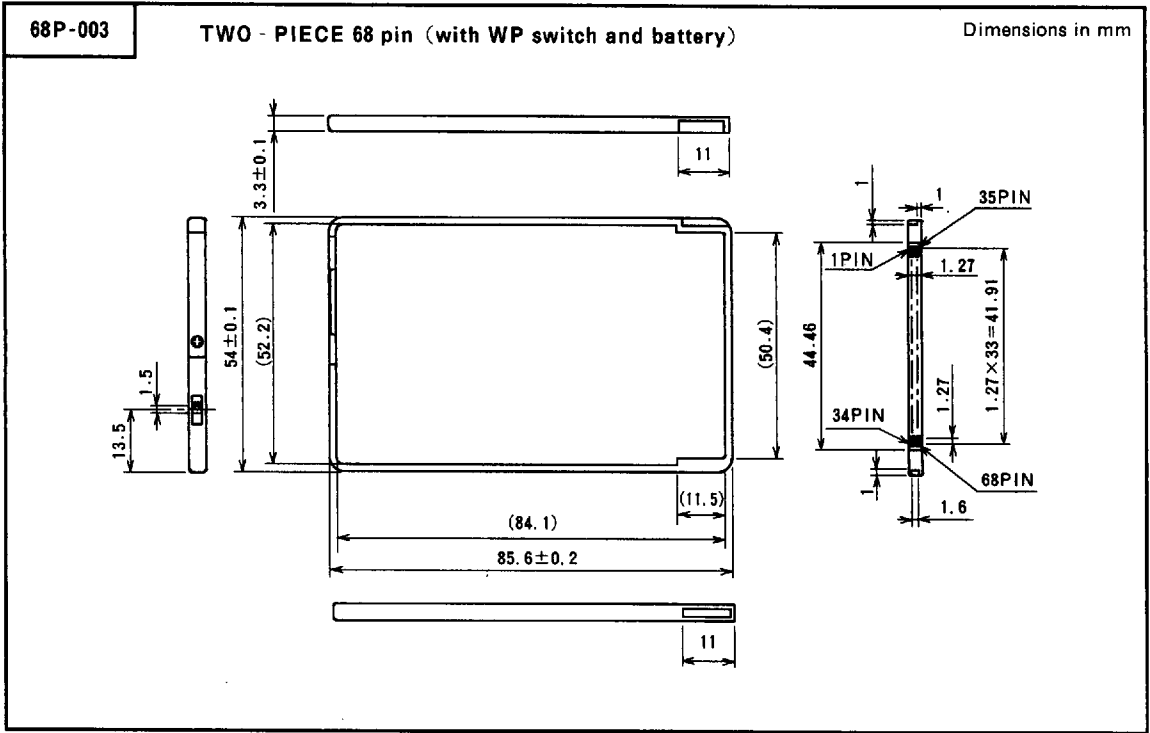
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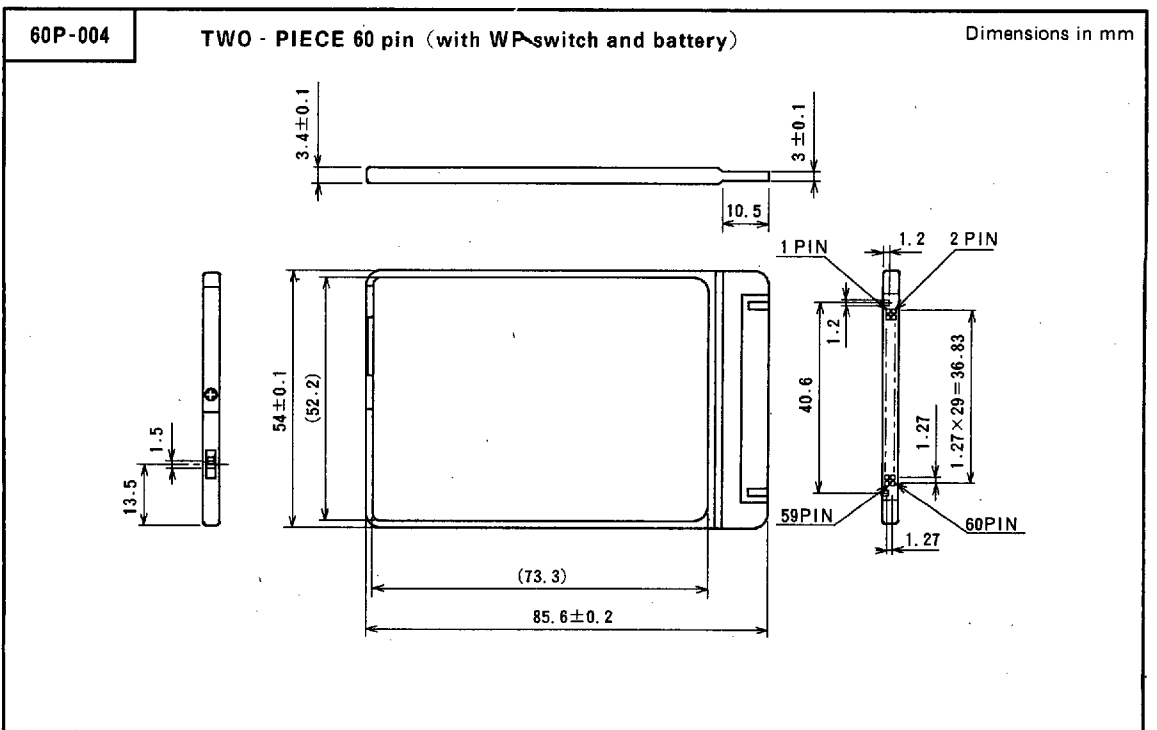
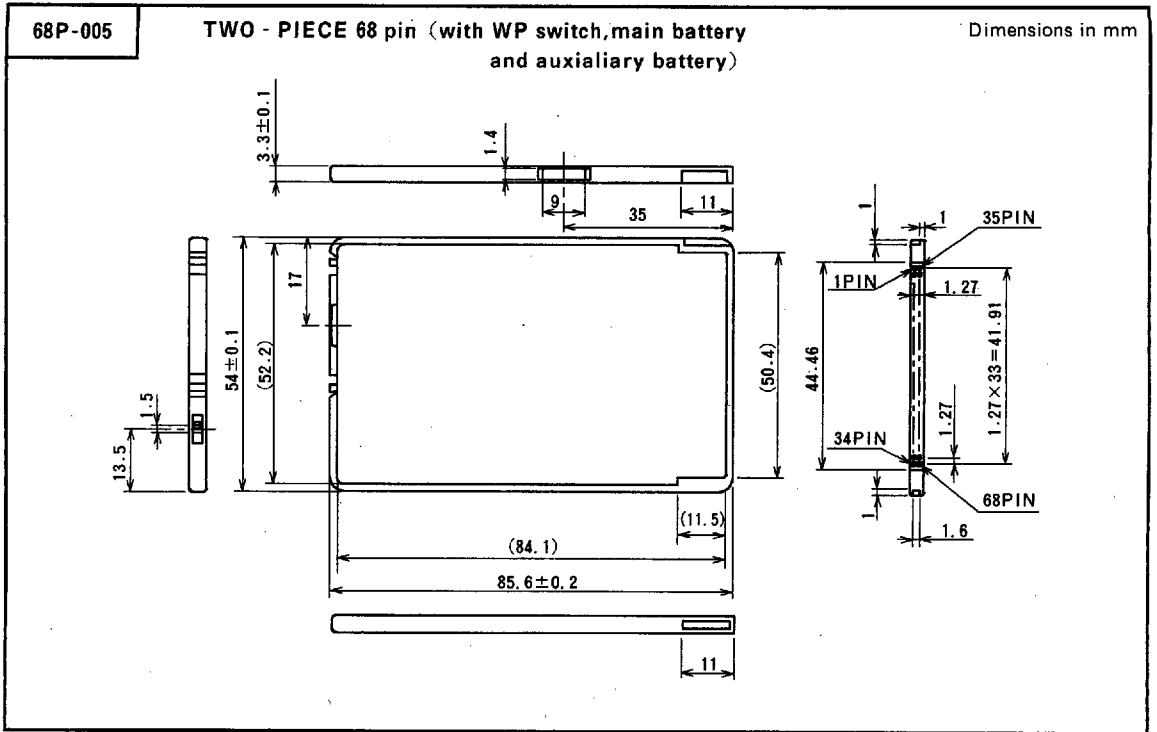
6249825 0029950 520

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6249825 0029951 467

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